

<b>Notice of References Cited</b>	Application/Control No. 10/600,513	Applicant(s)/Patent Under Reexamination TEH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,935,232	08-1999	Lambrecht et al.	710/315
*	B	US-6,011,792	01-2000	Miloslavsky, Alec	370/352
*	C	US-6,275,497	08-2001	Varma et al.	370/431
*	D	US-6,771,661	08-2004	Chawla et al.	370/468
*	E	US-6,999,432	02-2006	Zhang et al.	370/328
*	F	US-2002/0110116	08-2002	Aaltonen, Janne U.	370/352
*	G	US-2003/0174774	09-2003	Mock et al.	375/240.11
*	H	US-2004/0203835	10-2004	Trottier et al.	455/454
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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